

RICHARD WILKINS, Ph.D.

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CURRICULUM VITA

EDUCATION

- Ph.D. Physics, University of Michigan, Ann Arbor, MI 1991
- B.S. Physics, University of Pittsburgh, Pittsburgh, Pennsylvania, 1984

EXPERIENCE *(List all previous teaching and administrative positions held relative to Higher Ed.)*

- Prairie View A&M University
Professor, 2010 – Present
Courses: Physical Principles of Solid State Devices (Physical Electronics), Electromagnetic Field Theory, Photonic and Electronic Materials and Devices, Advanced Quantum Devices, Advanced Photonics, Advanced Characterization of Materials and Devices
- Teaching Assistant, 1984-1987, University of Michigan
Courses: Introductory Physics & Introductory Astronomy labs and recitations

PROFESSIONAL, TECHNICAL AND WORK-RELATED EXPERIENCE AND SKILLS

- Director, NASA Center for Radiation Engineering and Science for Space Exploration, 2008 – present.
- Director, Center for Applied Radiation Research, 2000 – present.

PROFESSIONAL ACHIEVEMENTS AND PUBLICATIONS *(5-7 most recent)*

- U. S. Patents: #7,407,640, “Functionalized Carbon Nanotube-Polymer Composites and Interactions with Radiation”, 2014.
- 2019: NASA Group Achievement Award, RAD-X Science Team, Langley Flight Research Center.
- S. Kyatsandra, M. Pulikkathara, and R. Wilkins, “X-ray radiation effects on thin film nanocomposites of functionalized and copper coated multi-walled carbon nanotube and poly(methyl methacrylate)”, accepted by Surfaces and Interfaces, Elsevier Press Vol. 17, 100362, available online: <https://doi.org/10.1016/j.surfin.2019.100362>.
- A. Akturk, J. McGarity, N. Goldman, D. Lichenwalner, B. Hull, D. Grider, and R. Wilkins, “Predicting Cosmic Ray Induced Failures in Silicon Carbide Power Devices”, IEEE Transactions on Nuclear Science Vol. 66 , Issue: 7 , pp. 1828-1832, 2019.
- A. Akturk, J. McGarrity, N. Goldman, D. Lichtenalner, B. Hull,, D. Grider and R. Wilkins, “Terrestrial Neutron-Induced Failures in Silicon Carbide Power MOSFETs and Diodes”, IEEE Transaction on Nuclear Science, Vol. 65, No. 6. pp. 1248-1253 (2018).